

# HER601 THRU HER608

### HIGH EFFICIENT SILICON RECTIFIER

Reverse Voltage - 50 to 1000 Volts Forward Current - 6.0 Ampere

#### **FEATURES**

- The plastic package carries Underwriters Laboratory Flammability Classification 94V-0
- Ultra fast switching for high efficiency
- Low reverse leakage
- High forward surge current capability
- High temperature soldering guaranteed: 250°C/10 seconds,0.375″(9.5mm) lead length, 5 lbs. (2.3kg) tension

#### **MECHANICAL DATA**

Case: R-6 molded plastic body

Terminals: Plated axial leads, solderable per MIL-STD-750,

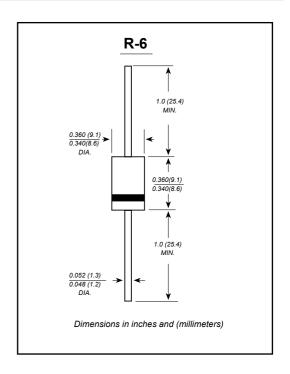
Method 2026

Polarity: Color band denotes cathode end

Mounting Position: Any

Weight: 0.072 ounce, 2.05 grams





#### MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

Ratings at 25°C ambient temperature unless otherwise specified. Single phase half-wave 60Hz,resistive or inductive load,for capacitive load current derate by 20%.

Characteristic	Symbol	HER 601	HER 602	HER 603	HER 604	HER 605	HER 606	HER 607	HER 608	Unit
Peak Repetitive Reverse Voltage Working Peak Reverse Voltage DC Blocking Voltage	VRRM VRWM VR	50	100	200	300	400	600	800	1000	٧
RMS Reverse Voltage	VR(RMS)	35	70	140	210	280	420	560	700	٧
Average Rectified Output Current (Note 1) @T <sub>A</sub> = 55°C	lo	6.0								Α
Non-Repetitive Peak Forward Surge Current 8.3ms Single half sine-wave superimposed on rated load (JEDEC Method)	lfsm	200								А
Forward Voltage @I <sub>F</sub> = 6.0A	VFM	1.0 1.3 1.7					V			
	IRM	10.0 100								μΑ
Reverse Recovery Time (Note 2)	trr	50 75						nS		
Typical Junction Capacitance (Note 3)	Cj	100 65							pF	
Operating Temperature Range	Tj	-65 to +150							°C	
Storage Temperature Range	Тѕтс	-65 to +150								°C

Note: 1. Leads maintained at ambient temperature at a distance of 9.5mm from the case

- 2. Measured with IF = 0.5A, IR = 1.0A, IRR = 0.25A. See figure 5.
- 3. Measured at 1.0 MHz and applied reverse voltage of 4.0V D.C.



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## **RATINGS AND CHARACTERISTIC CURVES**

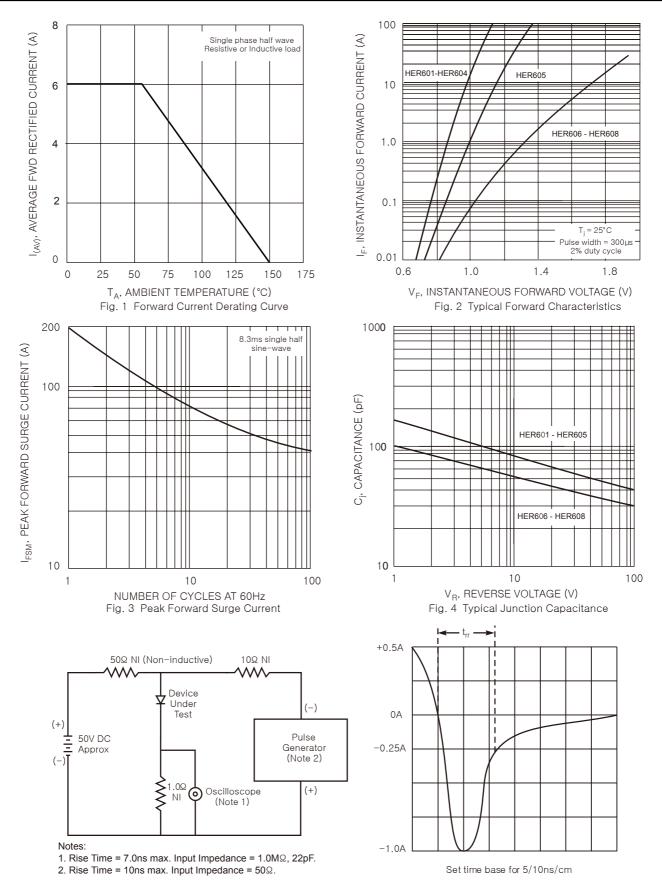


Fig. 5 Reverse Recovery Time Characteristic and Test Circuit